



PATENT  
Attorney Docket No.: 16869P-004610US  
Client Ref. No.: 219800332US2

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of:

Yukihiro Shibata et al.

Application No.: 10/761,493

Filed: January 20, 2004

For: METHOD AND APPARATUS FOR  
OBSERVING AND INSPECTING  
DEFECTS

Customer No.: 20350

Confirmation No. 4371

Examiner: Tu T. Nguyen

Technology Center/Art Unit: 2877

AMENDMENT UNDER 37 CFR 1.116  
EXPEDITED PROCEDURE EXAMINING  
GROUP 2877

**Mail Stop AF**

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Sir:

In response to the Final Office Action mailed August 8, 2005 on the above-referenced application, please enter the following amendments and remarks:

**Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.

**Remarks/Arguments** begin on page 5 of this paper.